

Form PTO-1449 INFORMATION DISCLOSURE CITATION IN AN APPLICATION (Use several sheets if necessary)		Docket Number 509982001200	Application Number 10/051,830
		Applicant	Xinhui NIU and Nickhil JAKATDAR
		Filing Date January 16, 2002	Group Art Unit To Be Assigned <i>2125</i>
		Mailing Date	February 28, 2002



U. S. PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Name	Class	Subclass	Filing Date If Appropriate

FOREIGN PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Country	Class	Subclass	Translation YES NO

OTHER DOCUMENTS

(including author, title, Date, Pertinent Pages, Etc.)

Examiner Initials	Ref. No.	Title
<i>AM</i>	1.	N. W. Ashcroft et al., "Solid State Physics", Saunders College, Philadelphia, 1976, pp. 133-134.
<i>AM</i>	2.	Ch. M. Bishop, "Neural Networks for Pattern Recognition", Clarendon Press-Oxford, 1995, Ch. 4., pp. 116-163.
<i>AM</i>	3.	O. S. Heavens, "Optical Properties of Thin Solid Films", Dover Publications Inc. N. Y. 1991 (book).
<i>AM</i>	4.	M. G. Moharam et al., "Rigorous coupled-wave analysis of planar-grating diffraction", J. Opt. Soc. Am. vol. 71, no. 7/July 1981, pp. 811-818.
<i>AM</i>	5.	W. H. Press et al., "Numerical Recipes", Cambridge University Press, 1986 (book).
<i>AM</i>	6.	J. A. Rice, "Mathematical Statistics and Data Analysis" sec. ed., ch. 14, Duxbury Press, 1995, pp. 507-570.

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MAR 15 2002

Technology Center 2100

EXAMINER: <i>Albert W. Paladino</i>	ALBERT W. PALADINO PATENT EXAMINER	DATE CONSIDERED: <i>8-18-05</i>
EXAMINER: Initial if citation considered, whether or not the citation conforms with MPEP 609. Draw a line through the citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.		

Form PTO-1449

INFORMATION DISCLOSURE CITATION
IN AN APPLICATION

(Use several sheets if necessary)



COPY OF PAPERS

ORIGINALLY FILED

Applicant

Application Number 10/051,830

Xinhui NIU and Nickhil JAKATDAR

Filing Date January 16, 2002

Group Art Unit 2121

Mailing Date March 14, 2002

U.S. PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Name	Class	Subclass	Filing Date If Appropriate

FOREIGN PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Country	Class	Subclass	Translation YES NO

OTHER DOCUMENTS

(including author, title, Date, Pertinent Pages, Etc.)

Examiner Initials	Ref. No.	Title
AMW	1.	Azzam et al., "Ellipsometry and Polarized Light", North Holland library, Amsterdam, 1987, book.
AMW	2.	Moharam et al., "Stable implementation of the rigorous coupled-wave analysis for surface - relief gratings: enhanced transmittance matrix approach", J. Opt. Soc. Am. vol. 12, no. 5, May 1995, pp. 1077-1086.

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EXAMINER: ALBERT W. PALADIN
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Form PTO-1449 INFORMATION DISCLOSURE CITATION IN AN APPLICATION <i>(Use several sheets if necessary)</i>	Docket Number 509982001200		Application Number 10/051,830
	Applicant Xinhui NIU and Nickhil JAKATDAR		
	Filing Date January 16, 2002		Group Art Unit 2124 2125
	Mailing Date April 11, 2003		

U.S. PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Name	Class	Subclass	Filing Date If Appropriate
Amr	1.	4/23/1985	4,513,384	Rozencwaig	—	—	RECEIVED
Amr	2.	12/19/1995	5,477,363	Matsuda	—	—	APR 18 2003
Amr	3.	12/23/1997	5,701,013	Hsia et al.	—	—	APR 18 2003
Amr	4.	1/23/2001	6,177,680 B1	Dick et al.	—	—	Technology Center 2100
Amr	5.	1/18/2002	6,407,396 B1	Mih et al.	—	—	Technology Center 2100
Amr	6.	11/12/2002	6,479,166 B1	Heuer et al.	—	—	—

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Examiner Initials	Ref. No.	Date	Document No.	Country	Class	Subclass	Translation YES NO

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(including author, title, Date, Pertinent Pages, Etc.)

Examiner Initials	Ref. No.	Title
Amr	7.	R. T. Chen et al., "Si-Based Surface-Relief Polygonal Gratings for 1-to-Many Wafer Scale Optical Clock Signal Distribution", IEEE Photonics Technology Letters, vol. 8, no. 8, August 1996, pp. 1038-1040.
Amr	8.	T. Khayim et al., "Ultrafast Unidirectional Deflection by Electrooptic Traveling Phase Grating Using Periodic Domain Inversion", IEEE, CLEO/Pacific Rim '99/Th03, 1999, pp. 726-727.
Amr	9.	S. Pelissier et al., "Fabrication of Buried Corrugated Waveguides by Wafer Direct Bonding", IEEE J. of Lightwave Tech. vol. 18, no. 4, April 2000.
Amr	10.	B. Pezeshki et al., "400-mW Single-Frequency 660-nm Semiconductor Laser", IEEE Photonics Tech. Letters, vol. 11, no. 7, July 1999, pp. 791-793.

 EXAMINER: ALBERT W. PALADIN AWP
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